

Supporting Information

All-round performance improvement of semitransparent perovskite solar cells by a pressure-assisted method

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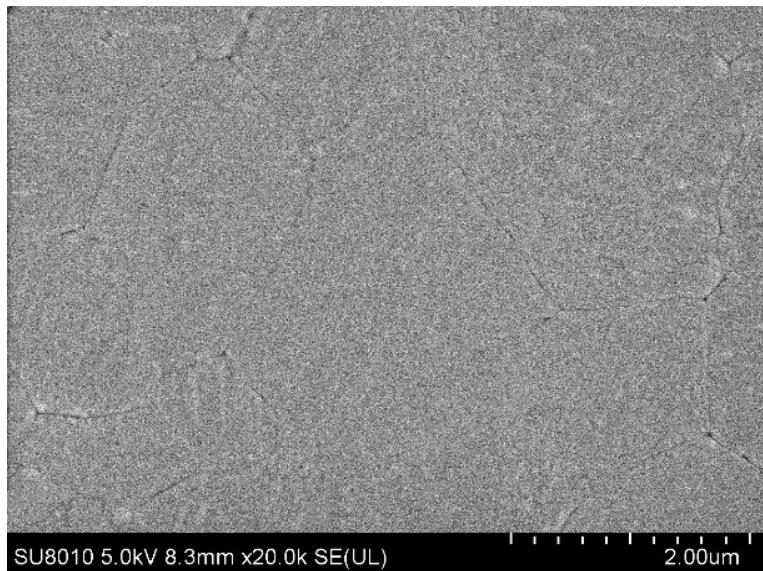


Fig. S1 The original SEM image of Fig. 2b.

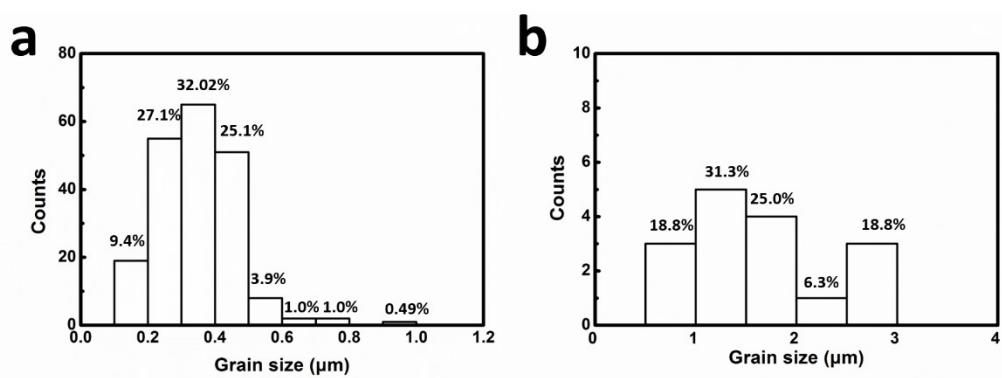


Fig. S2 Grain distribution statistics of (a) Fig. 2a and (b) Fig. 2b.

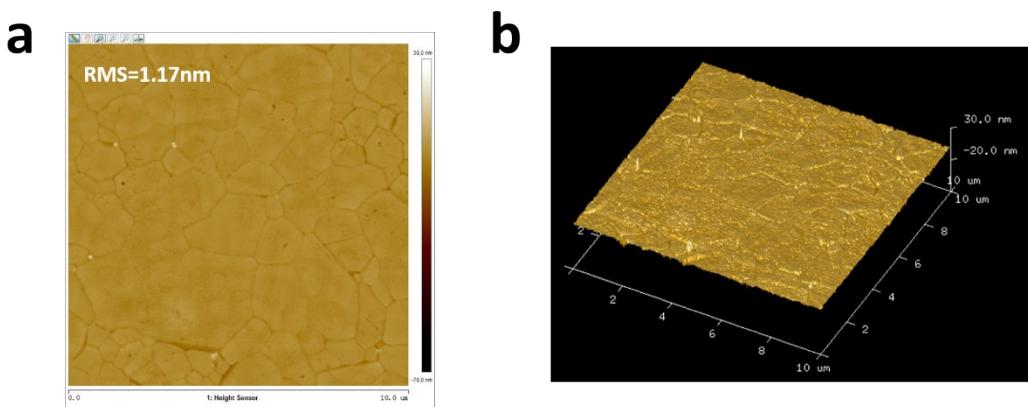


Fig. S3 (a) AFM topographic image and (b) three-dimensional topographic image of the TPR film.

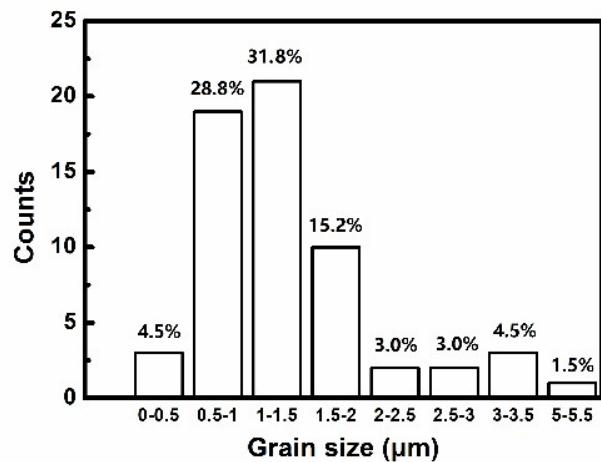


Fig. S4 Grain distribution statistics of Figure S3.

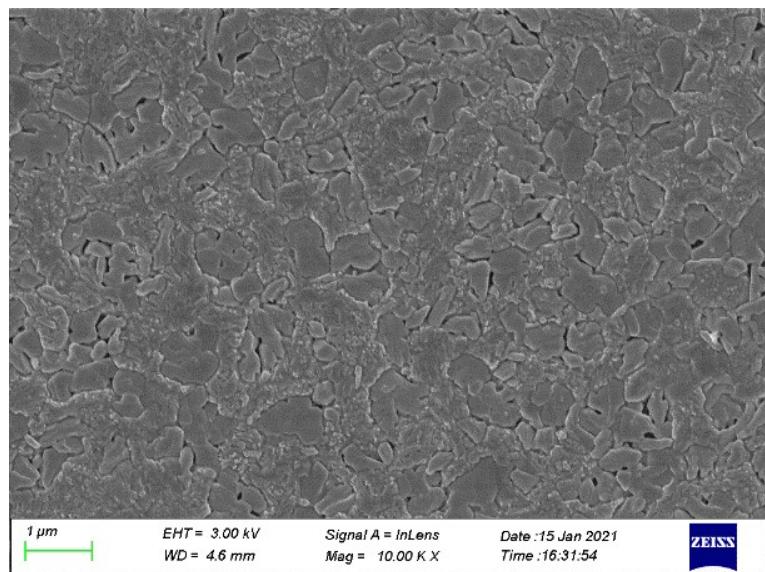


Fig. S5 Top view SEM image of the MAPbI₃ film annealed at 100 °C for 6 h at atmospheric pressure.

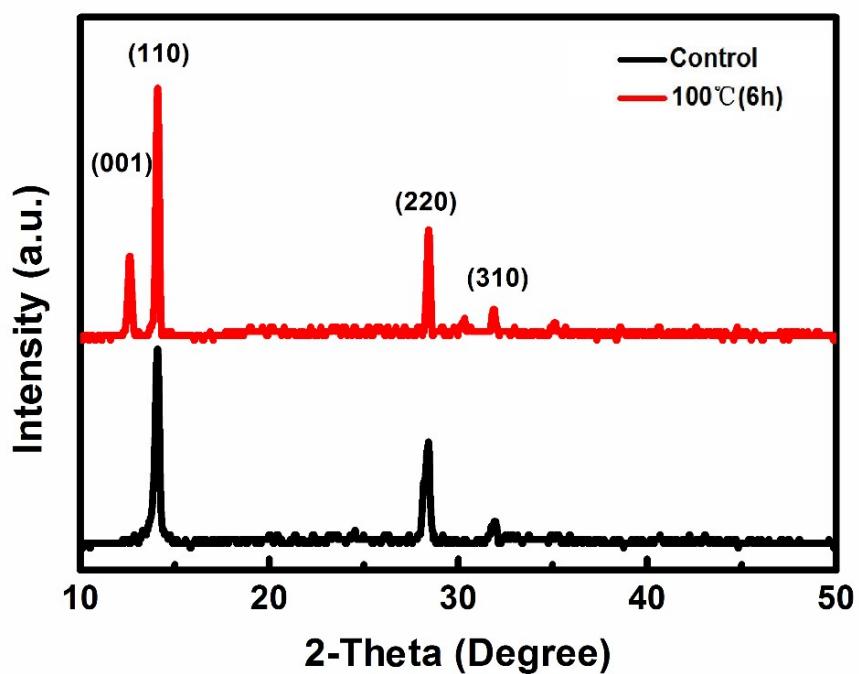


Fig. S6 XRD patterns of the precursor film and the MAPbI₃ film annealed at 100 °C for 6 h at atmospheric pressure.

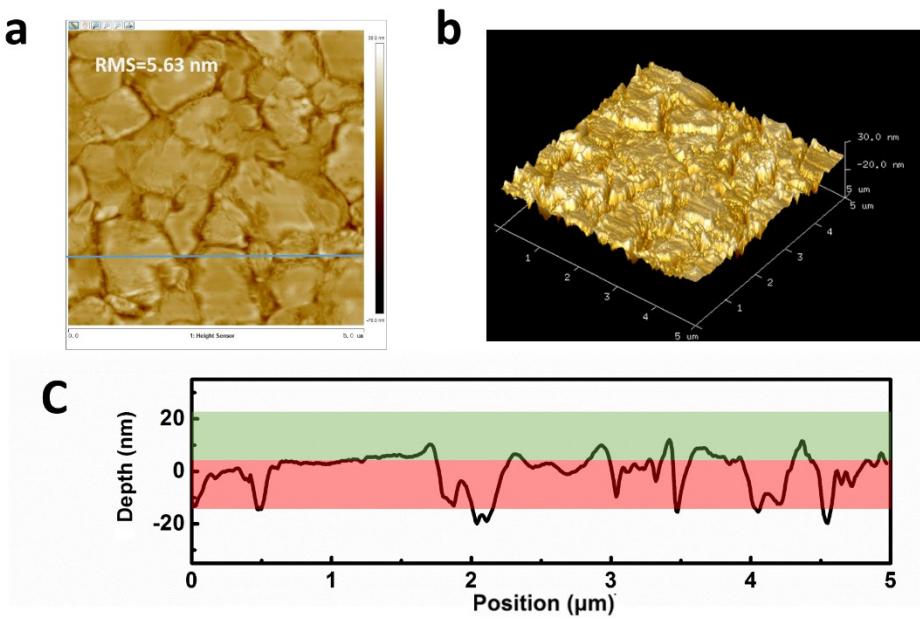


Fig. S7 (a) AFM topographic image, (b) three-dimensional topographic image and (c) surface profile of the MAPbI_3 film when 150 MPa used at room temperature for 6 h.

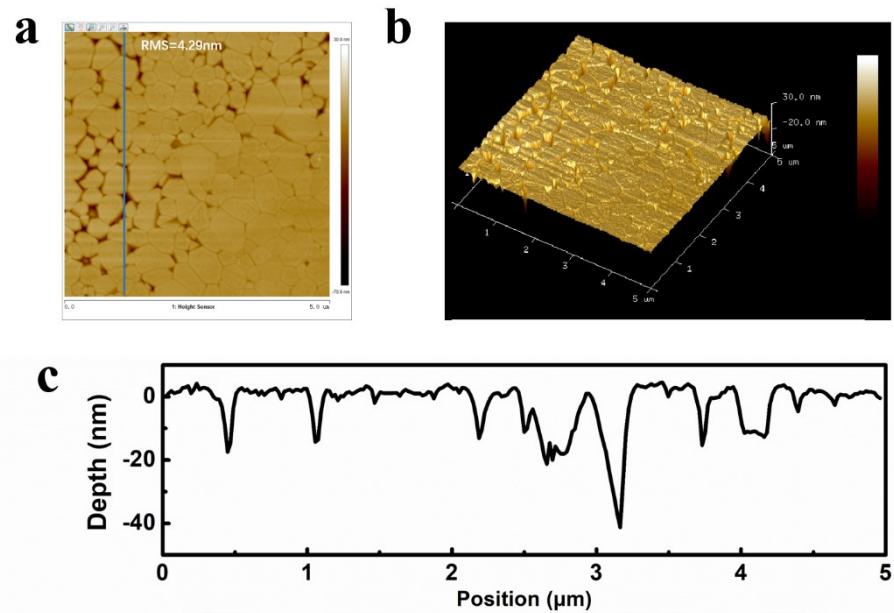


Fig. S8 (a) AFM topographic image, (b) three-dimensional topographic AFM image and (c) surface profile of MAPbI_3 film annealed at 100 °C with the pressure of 100 MPa for 6 h.

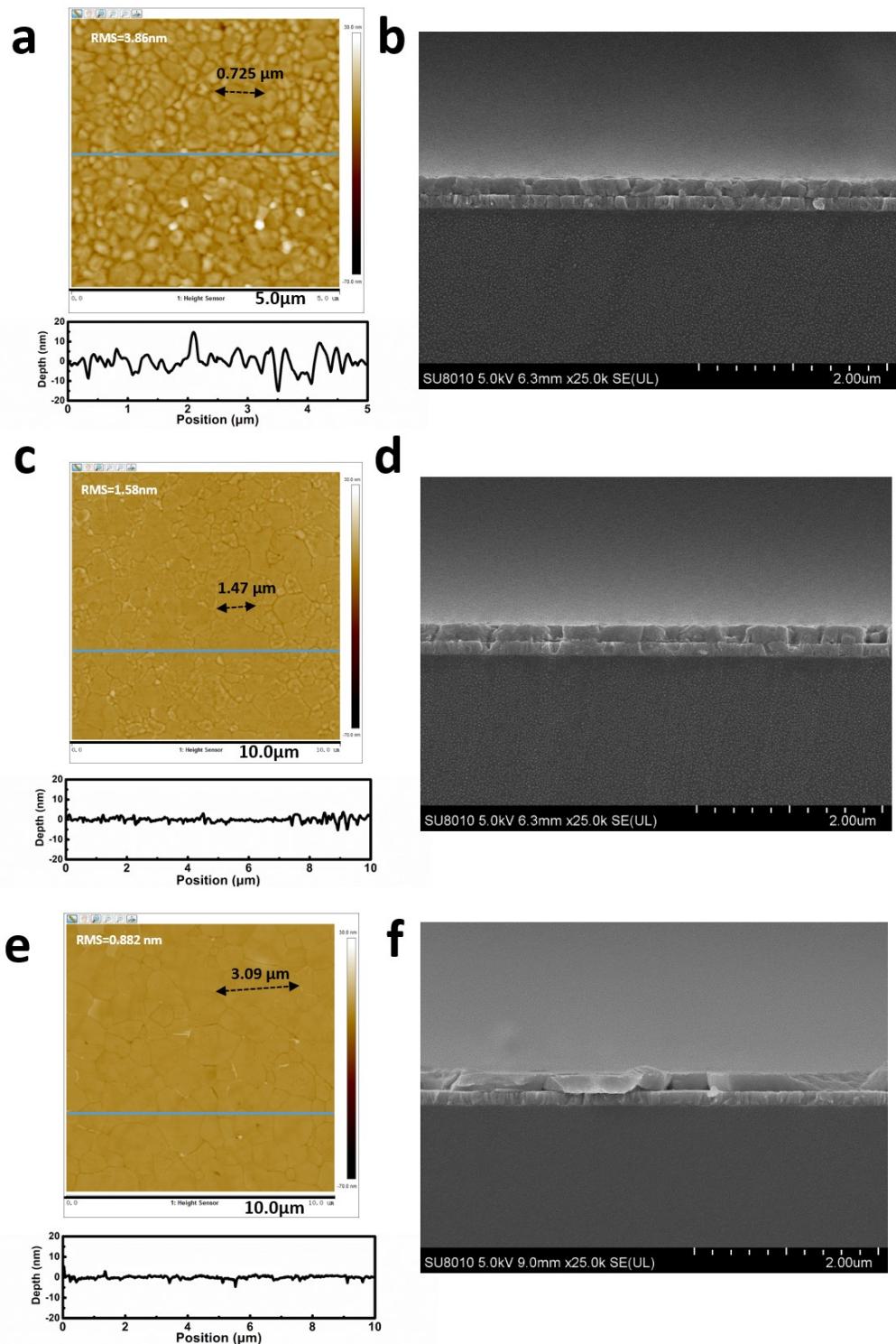


Fig. S9 (a) Top-view AFM image, (b) cross-sectional SEM images of the MAPbI_3 film with TPR treatment ($100\text{ }^\circ\text{C}$, 150 MPa for 1 h); (c) Top-view AFM image, (d) cross-sectional SEM images of the MAPbI_3 film with TPR treatment ($100\text{ }^\circ\text{C}$, 150 MPa for 3 h); (e) Top-view AFM image, (f) cross-sectional SEM images of the MAPbI_3 film with TPR treatment ($100\text{ }^\circ\text{C}$, 150 MPa for 5 h)

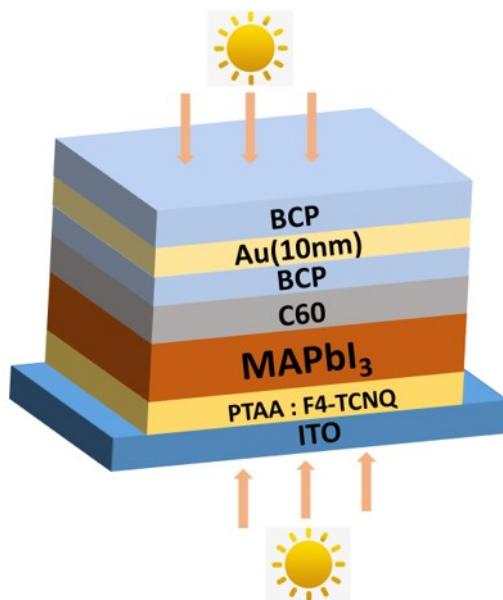


Fig. S10 Schematic device structure of SPSCs

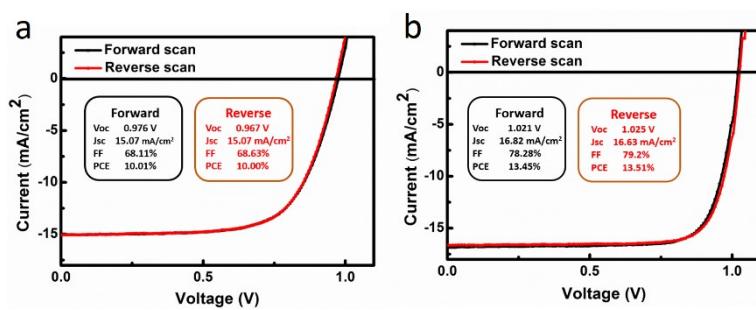


Fig. S11 Forward and reverse J-V scans at a 110 mV s⁻¹ scan rate of (a) control SPSC, and (b) TPR SPSC.

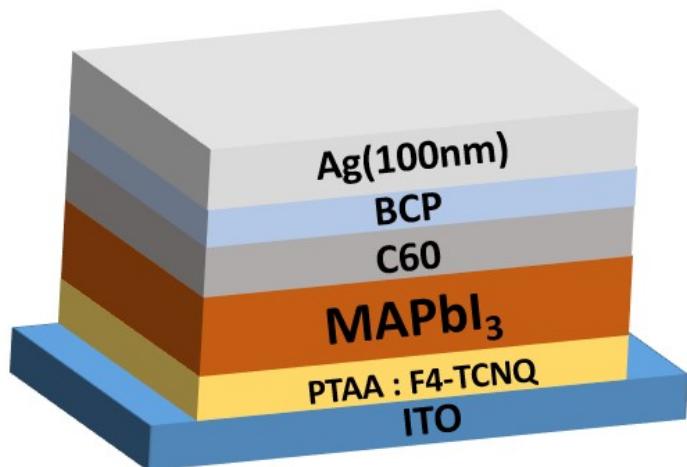


Fig. S12 Schematic device structure of Opaque PSCs.

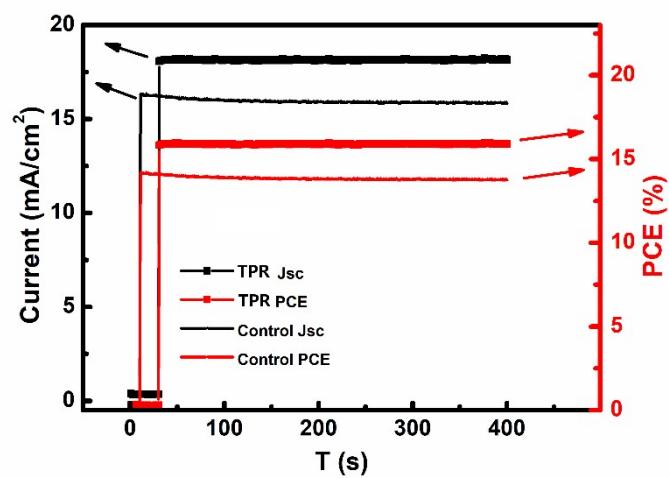


Fig. S13 400s steady-state photocurrent and power output at maximum power point of control PSCs and TPR PSCs.

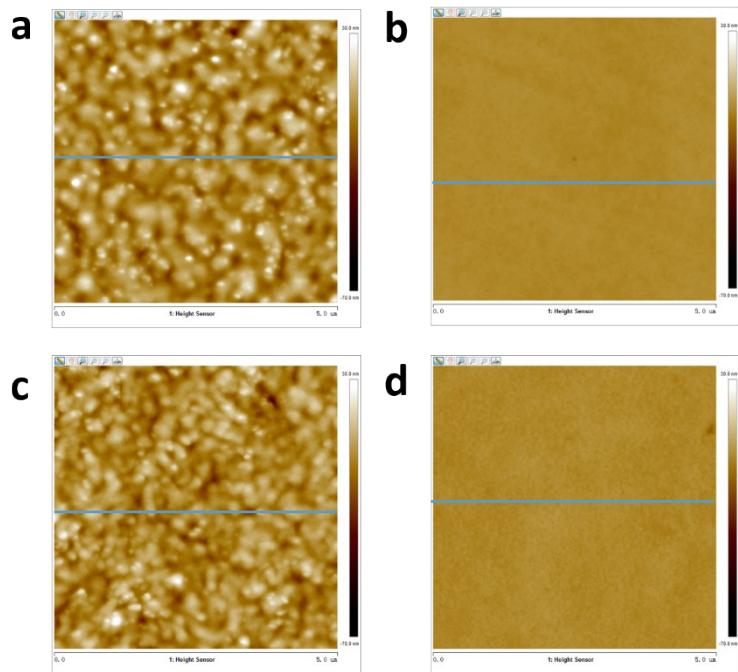


Fig. S14 AFM topographic images of composite films (ITO/PTAA/MAPbI₃/C₆₀/BCP) based on (a) precursor film and (b) TPR film; and Au electrodes (ITO/PTAA/MAPbI₃/C₆₀/BCP/Au) of (c) control SPSC and (d) TPR SPSC.

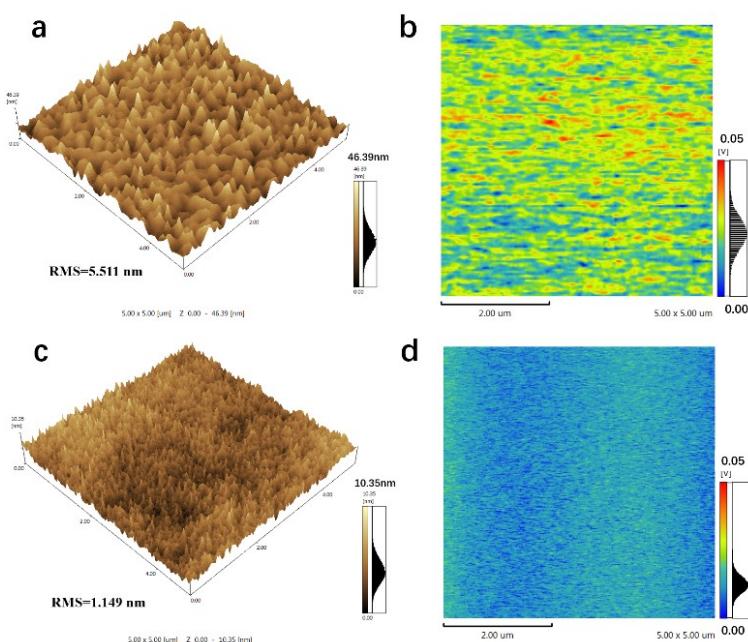


Fig. S15 (a) Three-dimensional topographic AFM image and (b) KFM image of Au electrode (ITO/PTAA/MAPbI₃/C₆₀/BCP/Au) based on control film; (c) Three-dimensional topographic AFM image and (d) KFM image of Au electrode (ITO/PTAA/MAPbI₃/C₆₀/BCP/Au) based on TPR film.

Table S1. Transmittance of control films and TPR films (PTAA/MAPbI₃) averaged over 5 films.

Sample number	1	2	3	4	5	Average
Control	25.85 %	26.71 %	26.53 %	25.74 %	25.41 %	26.05 %
TPR	26.83 %	28.17 %	28.75 %	26.11 %	27.82 %	27.54 %

Table S2. Sheet resistance of Au films based on the control films and TPR films

Sheet resistance (Ω/Sq square)	1	2	3	4	Average
Control	16.3	16.4	18.2	17.5	17.1
TPR	27.4	25	26.5	26.8	26.4